

Search Notes

Application/Control No.

10/069,750

Examiner

George R. Evanisko

Applicant(s)/Patent under
Reexamination

YOON ET AL.

Art Unit

3762

SEARCHED

Class	Subclass	Date	Examiner
600	16,17		
623	3.1,3.11,		
623	3.13,3.14		
623	3.16,3.17		
623	3.18,3.19	7/21/2005	✓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

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